Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK3126

Switching Regulator, Applications

Low drain–source ON resistance $RDS(ON) = 0.48 \Omega \text{ (typ.)}$

• High forward transfer admittance $: |Y_{fs}| = 7.5 \text{ S (typ.)}$

• Low leakage current : $IDSS = 100 \mu A (max) (VDS = 450 V)$

• Enhancement-mode : $V_{th} = 2.4 \sim 3.4 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	450	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	450	V
Gate-source voltage		V_{GSS}	±30	V
Drain current	DC (Note 1)	I _D	10	Α
	Pulse (Note 1)	I _{DP}	40	Α
Drain power dissipation	n (Tc = 25°C)	P_{D}	40	W
Single pulse avalanche energy (Note 2)		E _{AS}	222	mJ
Avalanche current		I _{AR}	10	Α
Repetitive avalanche energy (Note 3)		E _{AR}	4	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

Weight: 1.9 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal reverse, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal reverse, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

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Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 3.7 mH, R_{G} = 25 Ω , I_{AR} = 10 A

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device.

Please handle with caution.

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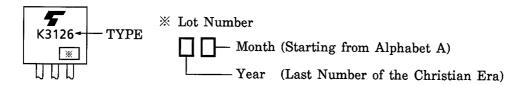
Electrical Characteristics (Ta = 25°C)

Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 450 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	450	_	_	V
Gate threshold v	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.4	_	3.4	V
Drain-source O	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 5 A	_	0.48	0.65	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 5 A	3.5	7.5	-	S
Input capacitano	:e	C _{iss}		_	1400	-	
Reverse transfe	rse transfer capacitance C_{rss} $V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$			240	-	pF	
Output capacitance		C _{oss}			590	-	
Switching time	Rise time	t _r	$V_{GS} = \pm 200V$ $V_{DD} = \pm 200V$	_	35	_	- ns
	Turn-on time	t _{on}		_	50	_	
	Fall time	t _f		_	80	_	
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\mathbf{w}} = 10 \mu s$	_	260	_	
Total gate charge (Gate-source plus gate-drain)		Qg			35		nC
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$	_	19	_	
Gate-drain ("miller") charge		Q_{gd}]		16		

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	10	Α
Pulse drain reverse current (Note 1)	I _{DRP}	-	_	_	40	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 10 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 10 A, V _{GS} = 0 V	_	1400	_	ns
Reverse recovery charge	Q _{rr}	dI _{DR} / dt = 100 A / μs		14	_	μC

Marking



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